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APPLICATION N	O. I	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/645,911 08/22/2003		08/22/2003	Hisatsugu Kurita	047297-0137	8557
22428	7590	08/03/2006		EXAMINER	
		DNER LLP	KORNAKOV, MICHAIL		
SUITE 500 3000 K STREET NW			ART UNIT	PAPER NUMBER	
WASHIN	GTON, DO	20007	1746		
			DATE MAILED: 08/03/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)
Office Action Summary		10/645,911	KURITA ET AL.
		Examiner	Art Unit
		Mikhail Kornakov	1746
- Period fo	<ul> <li>The MAILING DATE of this communication app</li> <li>Reply</li> </ul>	ears on the cover sheet with the c	orrespondence address
WHIC - Extension - If NO - Failure Any re	DRTENED STATUTORY PERIOD FOR REPLY HEVER IS LONGER, FROM THE MAILING DASIONS of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. period for reply is specified above, the maximum statutory period we to reply within the set or extended period for reply will, by statute, eply received by the Office later than three months after the mailing d patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tire will apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONE	nely filed the mailing date of this communication. (35 U.S.C. § 133).
Status			
1) 🖂	Responsive to communication(s) filed on 31 Ma	lay 2006.	
2a)⊠	This action is <b>FINAL</b> . 2b) ☐ This	action is non-final.	
3) 🗌	Since this application is in condition for allowar	nce except for formal matters, pro	osecution as to the merits is
	closed in accordance with the practice under E	Ex parte Quayle, 1935 C.D. 11, 4	53 O.G. 213.
Dispositio	on of Claims		
5) □ 6) ⊠ 7) □	Claim(s) 1-4 is/are pending in the application.  (a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed.  Claim(s) 1-4 is/are rejected.  Claim(s) is/are objected to.  Claim(s) are subject to restriction and/or		
Application	on Papers		
· <u> </u>	The specification is objected to by the Examine		
	The drawing(s) filed on is/are: a) acce		
	Applicant may not request that any objection to the		
	Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Ex	•	
Priority u	nder 35 U.S.C. § 119		
a)[	Acknowledgment is made of a claim for foreign All b) Some * c) None of:  1. Certified copies of the priority documents  2. Certified copies of the priority documents  3. Copies of the certified copies of the priority application from the International Bureau ee the attached detailed Office action for a list	s have been received. s have been received in Applicat rity documents have been receive u (PCT Rule 17.2(a)).	ion No ed in this National Stage
2)  Notice 3) Inform	e of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:	•

## **DETAILED ACTION**

- 1. By Applicants amendment of 05/31/2006 claims 6-10 are cancelled. Claim 1 is amended to include the limitation that the oxidizing step of the wafer with ozonated water takes place on the previously annealed wafer.
- 2. The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.
- 3. Claims 1-4 are rejected under 35 U.S.C. 102(b) as being anticipated by Nakajima
- 4. Nakajima discloses a method for cleaning a silicon wafer (abstract). The method consists of cleaning the wafer with ozone water (hydro cleaning), treating the wafer with hydrofluoric acid, and, as a final step, cleaning the wafer with ozone water, as denoted for the process (B) (0094). The concentrations of ozone water and hydrofluoric acid are within the claimed ranges ((0092), (0161), (0122)). Since the final step in the method of Nakajima is ozone water treatment, the oxide film is inherently present on the surface of the wafer after such final treatment with ozone water.

With regard to the microroughness of the cleaned silicon wafer, as per the instant claim 1, it is axiomatic that one who performs the steps of the known process must necessarily produce all of its advantages. Mere recitation of a newly discovered function or property that is inherently possessed by things in the prior art does not cause a claim drawn to these things to distinguish over the prior art, consult In Re Leinoff v. Louis Milona & Sons, Inc., 220 USPQ 845 (CAFC 1984).

With regard to oxidizing the annealed wafer, in [0030] Nakajima teaches that, according to one aspect of the invention, the following processes can be applied an

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arbitrary number of times and in **a non-specified order**: hydrofluoric acid processing as a **laser annealing preprocess**, oxidation processing, heat treatment, and **laser annealing**. FIG. 1B and corresponding description show some characteristics for TFT devices, wherein the active layers are: a crystalline semiconductor film in which hydrofluoric acid processing (HF processing) is performed after cleaning with ozone water (hydro cleaning) as a laser annealing preprocess (Process A); and a crystalline semiconductor film in which another ozone water processing (hydro cleaning) is performed additionally after the hydrofluoric acid processing (Process B), respectively. Each of the Process A and Process B is performed as the preprocess of the laser annealing, in the Step 3 (FIG. 1A).

Thus, all the limitations, including the new limitation of the instant claim 1, are met by Nakajima.

## **Response to Arguments**

5. Applicant's arguments filed 05/31/2006 have been fully considered but they are not persuasive. Applicants submit that Nakajima fails to disclose oxidizing an annealed silicon wafer with ozonized water. For this reason alone, Applicants submit that the outstanding rejection under 102 is improper and should be withdrawn.

In response to this, it is noted that Nakajima teaches oxidizing an annealed wafer by ....performing the following processes an arbitrary number of times and in <u>a non-specified order</u>: hydrofluoric acid processing as a laser annealing preprocess, oxidation processing, heat treatment, and laser annealing (see 0030), wherein the

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oxidation process may be performed utilizing ozone water processing [See the specific processing described in 0099].

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Other prior art reference cited in PTOL-892 show the oxidation of annealed wafers and their further cleaning.

## **Conclusion**

7. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Mikhail Kornakov whose telephone number is (571) 272-1303. The examiner can normally be reached on 9:00 - 5:30.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Barr can be reached on (571) 272-1414. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

M. Kepaa 1000 Primary Examiner Art Unit 1746

07/29/06